Program	Level of studies		First cycle		
	Program name		Physics		
Course name	PHYSICS OF THIN FILMS				
Course ID	Semester	Course status	ECTS	L+E	
PCM7411	VII	MANDATORY	4	2+0	
Lecturer	Doc. Dr. Maja Đekić				
Aims and intended learning outcomes	<ul> <li>Course objective is to familiarize students with production methods and properties of thin films.</li> <li>Learning outcomes: <ol> <li>Understands methods of thin films production</li> <li>Understands physical properties of thin films</li> <li>Understands different possibilities for thin film applications.</li> </ol> </li> </ul>				
	·c·	Course content miconductors. Structure			
real semiconductors. of doping states. De Statistics of electror properties. Boltzman	Energy spectrum efects in semicor as and holes in a kinetic equation	semiconductors. Electrons of carriers in real semiconductors. Intrinsic semicons semiconductors. Density n. Relaxation time. Elect ermomagnetic effects. Ma	onductors. Doping. E onductors. Extrinsic y of states. Fermi ric conductivity. Ha	Elementary theory semiconductors level. Transport	
	Student workload (hours)		Grading		
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Lectures and Exercis	. ,	Assessment		Points	
	. ,		method		
Lectures and Exercis	es 30	Tes	method st	Points	
Lectures and Exercise Exam preparation	es 30 40	Tes	method st er	Points 40	
Lectures and Exercis Exam preparation Assignments	es 30 40	Tes Pap Final e	method st er	Points 40 40	
Lectures and Exercis Exam preparation Assignments Other	es 30 40 30	Tes Pap Final e	method st er	Points 40 40	
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Lectures and Exercis Exam preparation Assignments Other Total 1. T. M. Neu Univerzit	es 30 40 30 100 nadović i T. M. Pavlo eta u Nišu, 1997.	Tes Pap Final e D Total	method st er exam lojeva, Institut za nukle	Points 40 40 20 100	
Lectures and Exercis Exam preparation Assignments Other Total 1. T. M. Neu Univerzit	es 30 40 30 100 nadović i T. M. Pavlo eta u Nišu, 1997.	Tes Pap Final e D Total Literature ović: Fizika i tehnika tankih sl	method st er exam lojeva, Institut za nukle	Points 40 40 20 100	